

ALL RIGHTS RESERVED. NO PORTION OF THIS PUBLICATION, WHETHER IN WHOLE OR IN PART CAN BE REPRODUCED WITHOUT THE EXPRESS WRITTEN CONSENT OF SPC TECHNOLOGY.

SPC-F005.DWG

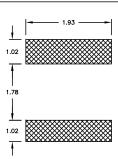
REVISIONS			DOC. NO. SPC-F005 * Effective: 7/8/02 * DCP No:						
DCP #	CP # REV DESCRIPTION		DRAWN	DATE	CHECKD	DATE	APPRVD	DATE	
2048	Α	RELEASED	JN	05/21/09	JWM	05/21/09	JWM	05/21/09	



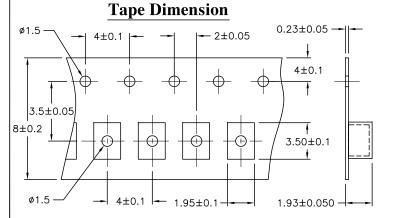
Features:

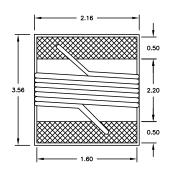
- Wire wound ceramic construction provide high SRF
- Ultra-compact inductors provide exceptional Q values
- Low profile, high current are available
- Miniature SMD chip inductor for fully autmated assembly
- Outstanding endurance from Pull-up force, mechanical shock and pressure
- tighter tolerance down to ±2%

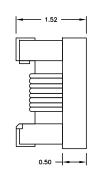
Recommended Pad Layout











DISCLAIMER:
ALL STATEMENTS AND TECHNICAL INFORMATION CONTAINED
HEREIN ARE BASED UPON INFORMATION AND/OR TESTS WE
BELIEVE TO BE ACCURATE AND RELIABLE. SINCE
CONDITIONS OF USE ARE BEYOND OUR CONTROL, THE
USER SHALL DETERMINE THE SUITABILITY OF THE PRODUCT
FOR THE INTENDED USE AND ASSUME ALL RISK AND
LIABILITY WHATSOEVER IN CONNECTION THEREWITH.

UNLESS OTHERWISE
SPECIFIED, DIMENSIONS ARE
FOR REFERENCE PURPOSES ONLY.

TOLERANCES:

DRAWN BY:	DATE:
Jason Nash	05/21/09
CHECKED BY:	DATE:
JWM	05/21/09
APPROVED BY:	DATE:
JWM	05/21/09

	DRAWING TITLE:								
)9		Wire Wour	nd Chip Inductor — C	ase si	ze 1206				
	SIZE	DWG. NO.		ELEC.	TRONIC FIL	E	REV		
9	Α	Ta-1119			Ta-1119.DWG				
9	SCAL	E: NTS	U.O.M.: Millimeters		SHEET:	1 OF	- 3		



Mfr PN	Inductance	Inductance Tolerance	DC Resistance Max	DC Current Rating	Self Resonant Frequency	Package	Q Factor	Test Frequency
MCWL06JT10N	10nH	± 5%	0.08ohm	1000mA	4.100MHz	1206	Q Factor:50	250MHz
MCWL06JT15N	15nH	± 5%	0.11ohm	1000mA	2.500MHz	1206	Q Factor:50	250MHz
MCWL06JT1R0	1000nH	± 5%	1.75ohm	370mA	0.290MHz	1206	Q Factor:35	25MHz
MCWL06JT22N	22nH	± 5%	0.12ohm	1000mA	2.400MHz	1206	Q Factor:55	250MHz
MCWL06JT33N	33nH	± 5%	0.14ohm	1000mA	1.600MHz	1206	Q Factor:60	250MHz
MCWL06JT47N	47nH	± 5%	0.16ohm	1000mA	1.500MHz	1206	Q Factor:65	200MHz
MCWL06JT68N	68nH	± 5%	0.20ohm	1000mA	1.300MHz	1206	Q Factor:65	200MHz
MCWL06JTR15	150nH	± 5%	0.70ohm	800mA	0.850MHz	1206	Q Factor:45	100MHz
MCWL06JTR22	220nH	± 5%	0.84ohm	500mA	0.700MHz	1206	Q Factor:45	100MHz
MCWL06JTR33	330nH	± 5%	1.05ohm	450mA	0.570MHz	1206	Q Factor:45	100MHz
MCWL06JTR47	470nH	± 5%	1.19ohm	470mA	0.450MHz	1206	Q Factor:45	50MHz
MCWL06JTR68	680nH	± 5%	1.47ohm	540mA	0.375MHz	1206	Q Factor:45	25MHz

Mechanical Performance

No.	Item	Specification	Test Methods			
1	Vibration Test	Appearance: No damage L change: within ±5% Q change; within ±10%	Test device shall be soldered on the substrate Oscillation Frequency: 10 to 55 to 10Hz for 1min Amplitude: 1.5mm Time: 2hrs for each axis (X, Y &Z), total 6hrs			
2	Resistance to Soldering-Heat	Q Change, within 210%	Solder Temperature: 270±5°C Immersion Time: 10±2sec			
3	Component Adhesion (Push Test)	1 lbs. For 0402 2 lbs. For 0603 3 lbs. For the rest	The device should be soldered (260±5°C for 10 seconds) to a tinned copper subs rate. A dynamiter force gauge should be applied to the side of the component. The device must with stand a minimum force of 2 or 4 pounds without a failure of adhesion on termination			
4	Drop Test	No damage	Dropping chip by each side and each corner. Drop 10 times in total Drop height:100cm Drop weight:125g			
5	Solderability Test	90% covered with solder.	Inductor shall be dipped in a melted solder bath at 245±5°C for 3 seconds.			
6	Resistance to Solvent Tes	No damage on appearance and marking.	MIL-STD202F, Method 215D			

Electrical Performance Test

No.	Item	Specification	Test Method			
1	Inductance		HP4291B			
2	Q		HP4291B			
3	SRF	Refer to standard electrical	HP8753D			
4	DC Resistance RDC	characteristic spec.	Micro-Ohm meter (Gom-801G)			
5	Rated Current IDC		Applied the current to coils, The inductance change should be less that 10% to initial value			
6	Over Load Test	Inductors shall have no evidence of electrical and mechanical damage	Applied 2 times of rated allowed DC current to inductor for a period of 5 minute			
7	Withstanding Voltage Test	Inductors shall be no evidence of electrical and mechanical damage.	AC voltage of 500 VAC applied between inductors terminal and case for 1 minute.			
8	Insulation Resistance Test	1000M ohm min	100 VDC applied between inductor terminal and case			

ALL RIGHTS RESERVED NO PORTION OF THIS PUBLICATION WE	ALL RIGHTS RESERVED. NO PORTION OF THIS PUBLICATION, WHETHER IN WHOLE OR IN PART CAN BE REPRODUCED WITHOUT THE		SIZE DWG. NO.			ELEC	REV	
EXPRESS WRITTEN CONSENT OF SPC TECHNOLOGY.	LEMEN IN THOSE ON IN 1980 DE NEI NOSSOLD IIINOOT ME	A		Ta-	-1119	То	ı-1119.DWG	Α
SPC-F005.DWG	DOC. NO. SPC-F005 * Effective: 7/8/02 * DCP No: 1398	SCALE	E: NTS		U.O.M.: INCHES [mm]	l	SHEET: 2 OF	- 3



Climatic Test

No.	Item	Specification	Test Method				
1	Temperature Characteristic		-40°C +125°C				
2	Humidity Test		Temperature: 40±2°C Relative Humidity: 90~95% Time: 96hrs±2hrs Measured after exposure in the room condition for 2hrs Temperature: -40±2°C Time: 96±2hrs Inductors are tested after 1 hour at room temperature				
3	Low Temperature Storage Test	Appearance: No damage L change: within ±10%					
4	Thermal Shock Test	Q change: within ±20%	One cycle: Step Temperature Time (min) 1 -25±3 30 2 25±2 15 3 125±3 30 4 25±2 15 Total: 5 cycles				
5	High Temperature Storage Test		Temperature:125±2 Time: 96±2hrs Measured after exposure in the room condition for 1hr				
6	High Temperature Load Life Test	There should be no evidence of	Temperature:85±2 Time:1000±12hrs f Load: Allowed DC current				
7	Humidity Load Life	short of open circuit.	Temperature: 40±2C Relative Humidity: 90~95% Time: 1000±12hrs Load: Allowed DC current				

LL RIGHTS RESERVED. NO PORTION OF THIS PUBLICATION, WHETHER IN WHOLE OR IN PART CAN BE REPRODUCED WITHOUT THE		SIZE	DWG. NO.		ELECTRONIC FILE		
EXPRESS WRITTEN CONSENT OF SPC TECHNOLOGY.			Ta	-1119	To	ı-1119.DWG	A
SPC-F005.DWG	DOC. NO. SPC-F005 * Effective: 7/8/02 * DCP No: 1398	SCALE	E: NTS	U.O.M.: INCHES [mm]]	SHEET: 3 OF	F 3